


<b>Search Notes</b>  	<b>Application/Control No.</b>  10762536	<b>Applicant(s)/Patent Under Reexamination</b>  SUH ET AL.
	<b>Examiner</b>  BENJAMIN E LANIER	<b>Art Unit</b>  2432

SEARCHED			
Class	Subclass	Date	Examiner
726	26-27	5/5/2010	BL
713	189, 193	5/6/2010	BL

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--